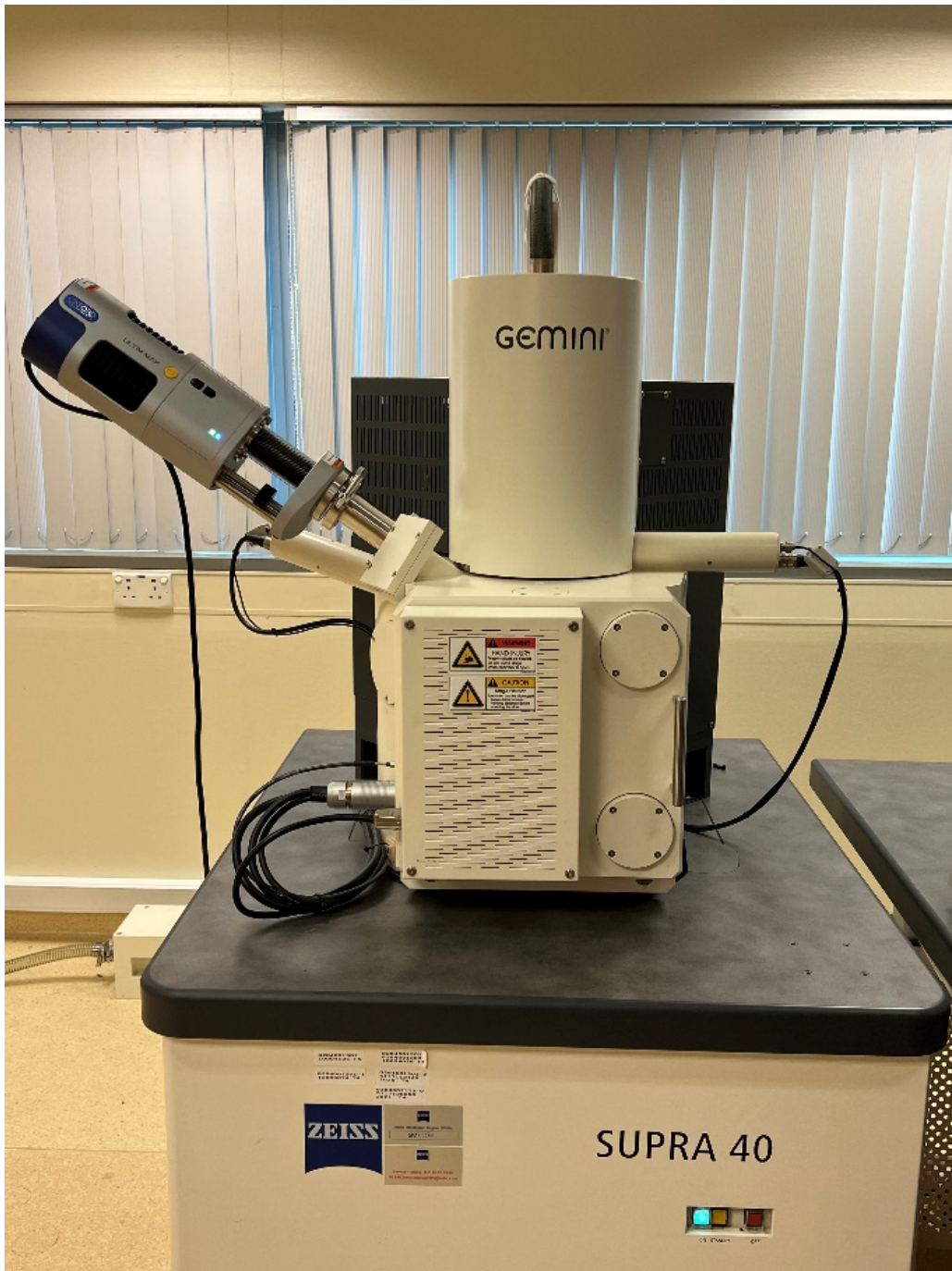


Scanning Electron Microscope (SEM); Zeiss Supra 40



The Zeiss Supra 40 FE SEM is the Schottky field emission (SFE) source provides excellent beam brightness, unsurpassed probe current stability and probe current suitable for quantitative analytical applications.

It is equipped with the Oxford Eds AztecLive 60mm² area. It has the new Live Chemical Imaging mode that enables you to view sample morphology and elemental distribution, simultaneously and continuously as you move around your sample.